

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10519988	SCHARNWEBER ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Young J Kim	1637

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Patent Databases (USPT, USPPG, EPO, JPO, DERWENT, IBM-TDB)	2/27/2008	YJK
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Patent Databases (USPT, USPPG, EPO, JPO, DERWENT, IBM-TDB)	12/10/2008	/YJK/
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### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

	/Young J Kim/ Primary Examiner.Art Unit 1637
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